DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power PNP, based on type 2N4033		
Number:	5202/008	Issue:	8

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diodes, Silicon, Switching, based on types 1N5807, 1N5809, 1N5811 and 1N5811U		
Number:	5101/013	Issue:	8

Other documents affected:

5101/014-7, 5101/026-8, 5101/027-7, 5103/029-14, 5103/031-11, 5103/032-5, 5103/033-5, 5106/016-12, 5106/017-9, 5106/018-9, 5106/019-10, 5106/020-7, 5106/021-7, 5106/023-9, 5106/024-7, 5201/001-9, 5201/002-11, 5201/003-6, 5201/004-9, 5201/006-7, 5201/011-7, 5201/019-11, 5201/020-5, 5202/001-12, 5202/002-6, 5202/008-8, 5202/014-11, 5203/004-6, 5203/010-12, 5203/011-6, 5203/016-8, 5204/002-11, 5204/006-8, 5207/002-12, 5207/003-6, 5207/005-10, 5207/009-5

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diodes, Silicon, Power Schottky Rectifier based on Types 1N5822 and 1N5822U		
Number:	5106/020	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diode, Silicon Switching, based on type 1N6640U		
Number:	5101/027	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power NPN, based on type 2N2222A		
Number:	5201/002	Issue:	11

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power PNP, based on type 2N5401		
Number:	5202/014	Issue:	11

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diodes, Silicon, Switching, based on types 1N5802, 1N5804, 1N5806, 1N5802US, 1N5804US,		
Number:	5101/014	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors High Power PNP, based on type BUX78		
Number:	5204/006	Issue:	8

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors High Power NPN, based on type BUX77		
Number:	5203/016	Issue:	8

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diode, Rectifier, High Voltage based on types STTH40200 and STTH60200		
Number:	5103/033	Issue:	5

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors High Power NPN, based on types 2N3439 and 2N3440		
Number:	5203/011	Issue:	6

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors, Low Power, NPN, based on type 2N3700		
Number:	5201/004	Issue:	9

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors, Matched Dual, NPN, based on types 2N2919, 2N2920 and 2N2920A		
Number:	5207/002	Issue:	12

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power PNP, based on type 2N2905A		
Number:	5202/002	Issue:	6

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power PNP, based on type 2N2907A		
Number:	5202/001	Issue:	12

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors, High Voltage, NPN, based on type 2N5551		
Number:	5201/019	Issue:	11

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors, Low Power, NPN, based on type 2ST15300		
Number:	5201/020	Issue:	5

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors, Matched Dual, PNP, based on type 2N3350		
Number:	5207/003	Issue:	6

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors High Power PNP, based on type 2N5153		
Number:	5204/002	Issue:	11

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power NPN, based on type 2N2219A		
Number:	5201/003	Issue:	6

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker	
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat	
Status: IMPLEMENTED			

Title:	Transistors High Power NPN, based on type 2N5154		
Number:	5203/010	Issue:	12

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power RF NPN, based on type 2N3019		
Number:	5201/011	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker	
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat	
Status: IMPLEMENTED			

Title:	Transistors High Power NPN, based on type 2N5672		
Number:	5203/004	Issue:	6

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power NPN, based on type 2N2369A		
Number:	5201/006	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker	
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat	
Status: IMPLEMENTED			

Title:	Transistors, Matched Dual, PNP, based on types 2N3810		
Number:	5207/005	Issue:	10

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors Low Power NPN, based on type 2N2484		
Number:	5201/001	Issue:	9

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diode, Power, Schottky Rectifier, based on Type STPS80A45C and STPS40A45C		
Number:	5106/024	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diode, Rectifier, High Voltage, Surface Mount Based on type STTH60400		
Number:	5103/032	Issue:	5

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diode, Silicon, Power Schottky Rectifier, based on Type 1N5819		
Number:	5106/021	Issue:	7

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diode, Power, Schottky Rectifier based on Type STPS80A150C, STPS60A150C and STPS40A150C		
Number:	5106/023	Issue:	9

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Transistors, Low Power, Complementary NPN/PNP Based on type 2ST3360		
Number:	5207/009	Issue:	5

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

DOCUMENT CHANGE REQUEST

DCR number 1788	Changes required for: General	Originator: Steve Thacker
Date: 2026/07/16	Date sent: 2026/01/05	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Diodes, Silicon, Switching, based on types 1N6642 and 1N6642U		
Number:	5101/026	Issue:	8

Other documents affected:

Page:

various

Paragraph:

Appendix A (for STMICROELECTRONICS (F))

Original wording:

As per current issue as above

Proposed wording:

In Appendix A (for STMICROELECTRONICS (F)) in each listed Detail Specification (see above) remove from the current deviation to Para. 2.1.1, the specific reference to ESCC No. 20400 (that permits it to be replaced MIL-STD-750 test Methods (i.e. 2072, 2078 and/or 2069 (depending on the affected ESCC Detail spec))
(ref. DCR1365 when this specific deviation was implemented into all the same ESCC Detail specs)

e.g.
In ESCC 5101/013 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2078..

In ESCC 5207/009 Appendix A 1st item Para. 2.1.1, Deviations from the Generic Specification: Para. 8, Test Methods and Procedures, remove the 1st bullet:
• No. 20400, Internal Visual Inspection: replaced by MIL-STD-750 Test Method 2072..

Justification:

This DCR is raised on behalf of Manufacturer ST.

ST advises that they no longer need to apply the deviation on ESCC No. 20400.

Attachments:
N/A
Modifications:
N/A
Approval signature:

Date signed:
2026-07-16